

**Search Notes**

Application/Control No.

10/731,832

Examiner

Khanh V. Nguyen

Applicant(s)/Patent under  
Reexamination

HAJIMIRI ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	277	5/23/2005	NKV
330	310		
330	311		
330	296		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR